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Application/Control No.	Applicant(s)/Patent under Reexamination
09/943,347	TAKEO, HIDEYA
Examiner	Art Unit
Christopher L. Lavin	2621

	SEAR	CHED	* '
Class	Subclass	Date	Examiner
382	128,159, 130-132, 160, 170	6/22/2005	CLL
382	190, 199	6/22/2005	CLL
382	203	6/22/2005	CLL
382	256-265	6/22/2005	CLL
128	920	6/22/2005	CLL
128	922-925	6/22/2005	CLL
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
		DATE	EXMR
East Search		6/22/2005	CLL
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